

Notice of References Cited	Application/Control No. 10/593,254		Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL.	
	Examiner JOSEPH MILLER JR		Art Unit 1792	Page 1 of 1

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*	B	US-6,984,591	01-2006	Buchanan et al.	438/778
*	C	US-7,070,833	07-2006	Smith et al.	427/255.23
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.